

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10596294	WAKIYAMA, KOJI
	<b>Examiner</b>	<b>Art Unit</b>
	Jason Heidemann	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
348	61,77,78,207.99,207.1,156	10/14/2009	/JEH/
340	5.2,5.52,5.53,5.8,5.82,5.83,540,426.1	10/14/2009	/JEH/
351	200,205,206,209	10/14/2009	/JEH/
382	100,115,117,118	10/14/2009	/JEH/
396	155,14,18,	10/14/2009	/JEH/
713	182,185,186	10/14/2009	/JEH/

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Searched Class and Subclass with Keywords (iris, focus, authentication, etc)	10/14/2009	/JEH/
Searched Google, ACM, and IEEE with keywords (iris focus, multiple focus ranges, etc)	10/14/2009	/JEH/
Author Search conducted on East	10/14/2009	/JEH/
Author Search Conducted on Googe, ACM, and IEEE	10/14/2009	/JEH/

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>